



TGD P-Channel Enhancement Mode Power MOSFET

Description

The TGD60P25K uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge .This device is well suited for high current load applications.

General Features

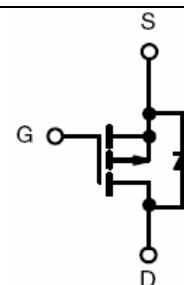
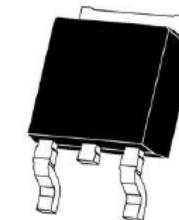
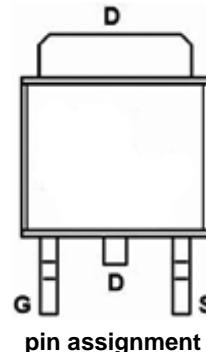
- $V_{DS} = -60V, I_D = -25A$
- $R_{DS(ON)} < 45m\Omega @ V_{GS} = -10V$
- High density cell design for ultra low $R_{DS(on)}$
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

- High side switch for full bridge converter
- DC/DC converter for LCD display

100% UIS TESTED!

100% ΔV_{ds} TESTED!

**Schematic diagram****TO-252 -2Ltop view****Package Marking and Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
60P25K	60P25K	TO-252-2L	-	-	-

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	-60	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	-25	A
Drain Current-Continuous($T_c=100^\circ C$)	$I_D (100^\circ C)$	-17.7	A
Pulsed Drain Current	I_{DM}	-60	A
Maximum Power Dissipation	P_D	90	W
Derating factor		0.72	W/ $^\circ C$
Single pulse avalanche energy (Note 5)	E_{AS}	300	mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 150	$^\circ C$



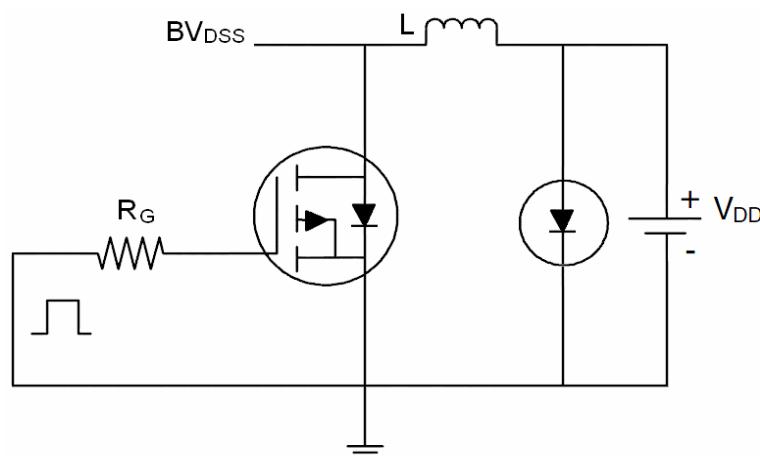
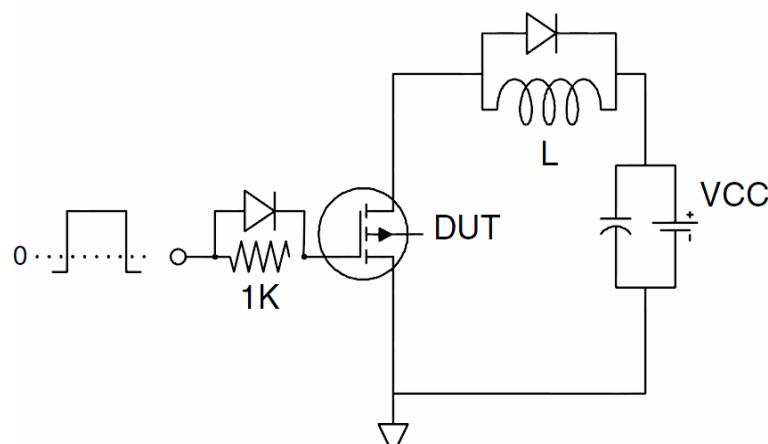
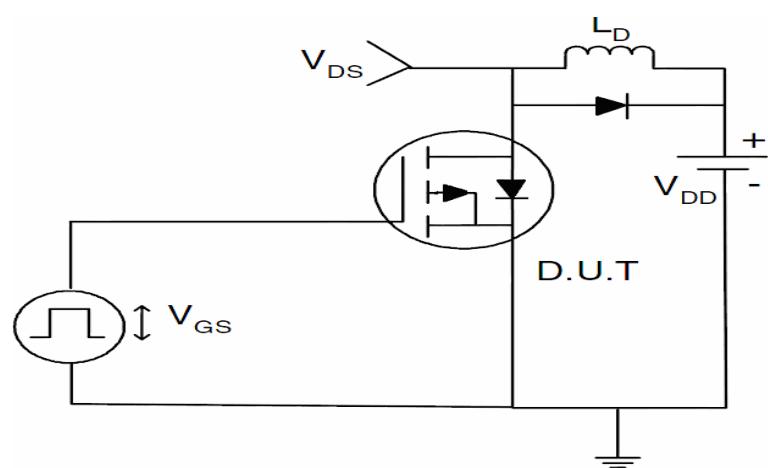
Thermal Resistance, Junction-to-Case ^(Note 2)	$R_{\theta JC}$	1.4	$^{\circ}\text{C}/\text{W}$
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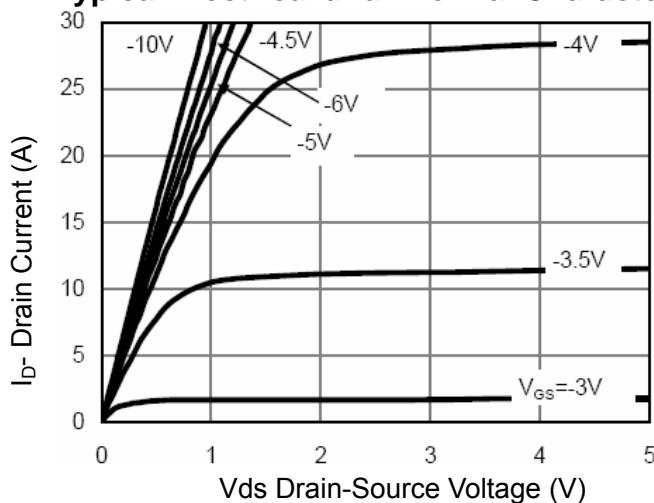
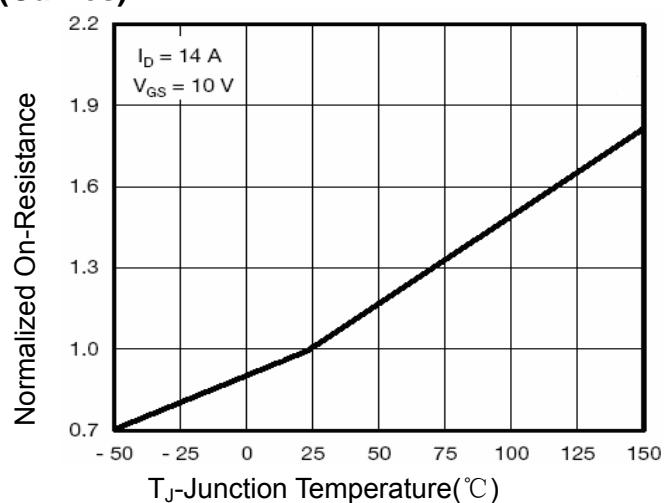
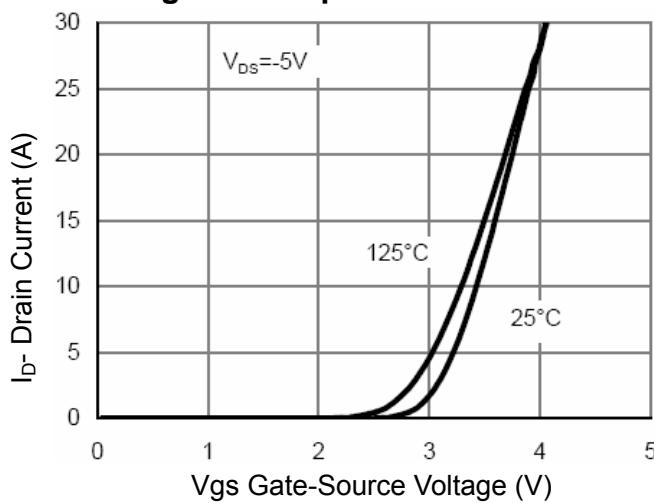
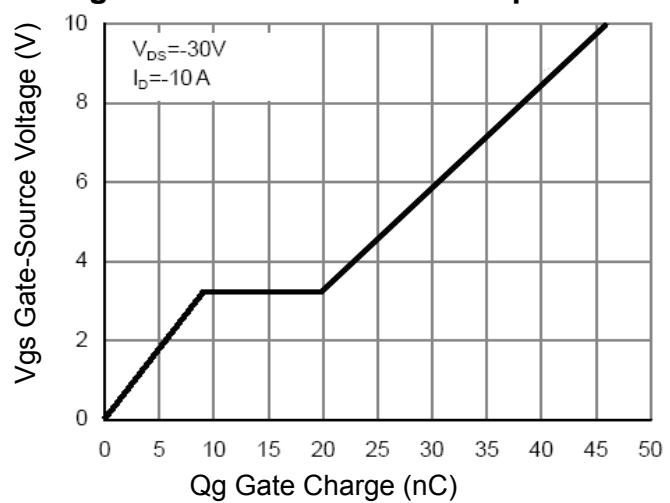
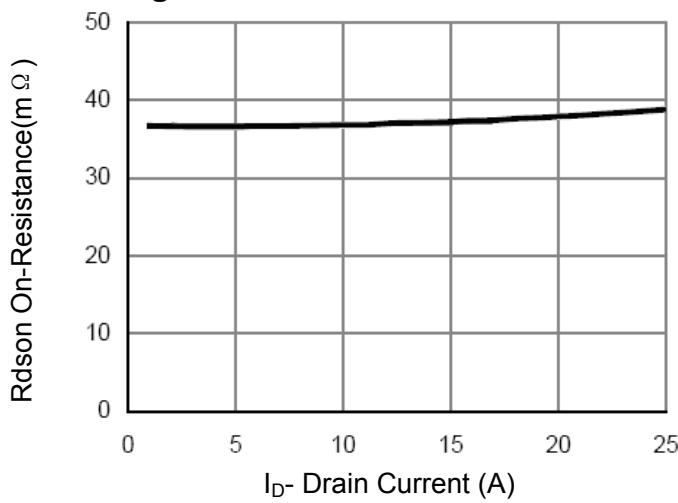
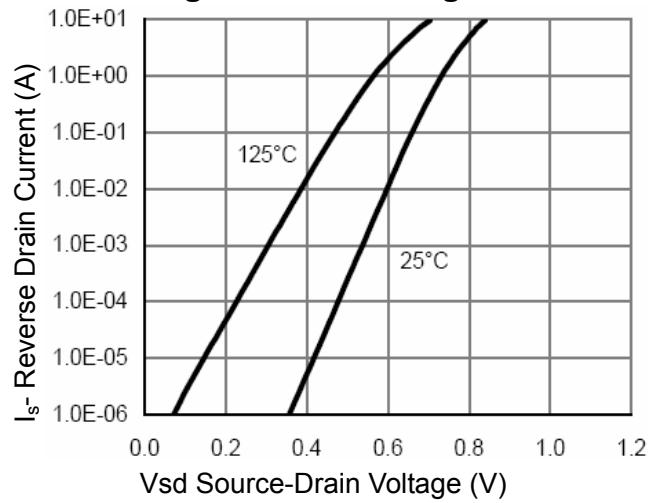
Electrical Characteristics ($T_c=25^{\circ}\text{C}$ unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-60	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}}=-60\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-1	μA
Gate-Body Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	±100	nA
On Characteristics ^(Note 3)						
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=-250\mu\text{A}$	-2	-2.6	-3.5	V
Drain-Source On-State Resistance	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-20\text{A}$	-	37	45	$\text{m}\Omega$
Forward Transconductance	g_{FS}	$V_{\text{DS}}=-10\text{V}, I_{\text{D}}=-10\text{A}$	-	25	-	S
Dynamic Characteristics ^(Note 4)						
Input Capacitance	C_{iss}	$V_{\text{DS}}=-30\text{V}, V_{\text{GS}}=0\text{V}, F=1.0\text{MHz}$	-	3430	-	PF
Output Capacitance	C_{oss}		-	391	-	PF
Reverse Transfer Capacitance	C_{rss}		-	272	-	PF
Switching Characteristics ^(Note 4)						
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}}=-30\text{V}, R_{\text{L}}=1.5\Omega, V_{\text{GS}}=-10\text{V}, R_{\text{G}}=3\Omega$	-	12	-	nS
Turn-on Rise Time	t_{r}		-	15	-	nS
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$		-	38	-	nS
Turn-Off Fall Time	t_{f}		-	15	-	nS
Total Gate Charge	Q_{g}	$V_{\text{DS}}=-30, I_{\text{D}}=-20\text{A}, V_{\text{GS}}=-10\text{V}$	-	46	-	nC
Gate-Source Charge	Q_{gs}		-	9.5	-	nC
Gate-Drain Charge	Q_{gd}		-	10.5	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage ^(Note 3)	V_{SD}	$V_{\text{GS}}=0\text{V}, I_{\text{S}}=-10\text{A}$	-		-1.2	V
Diode Forward Current ^(Note 2)	I_{S}		-	-	-25	A
Reverse Recovery Time	t_{rr}	$T_J = 25^{\circ}\text{C}, IF = -10\text{A}$ $di/dt = -100\text{A}/\mu\text{s}$ ^(Note 3)	-	47	-	nS
Reverse Recovery Charge	Q_{rr}		-	53	-	nC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production
5. E_{AS} condition: $T_J=25^{\circ}\text{C}, V_{\text{DD}}=-20\text{V}, V_{\text{G}}=-10\text{V}, L=1\text{mH}, R_{\text{G}}=25\Omega, I_{\text{AS}}=33\text{A}$

Test Circuit
1) E_{AS} Test Circuit

2) Gate Charge Test Circuit

3) Switch Time Test Circuit


Typical Electrical and Thermal Characteristics (Curves)

Figure 1 Output Characteristics

Figure 4 Rdson-Junction Temperature

Figure 2 Transfer Characteristics

Figure 5 Gate Charge

Figure 3 Rdson- Drain Current

Figure 6 Source- Drain Diode Forward

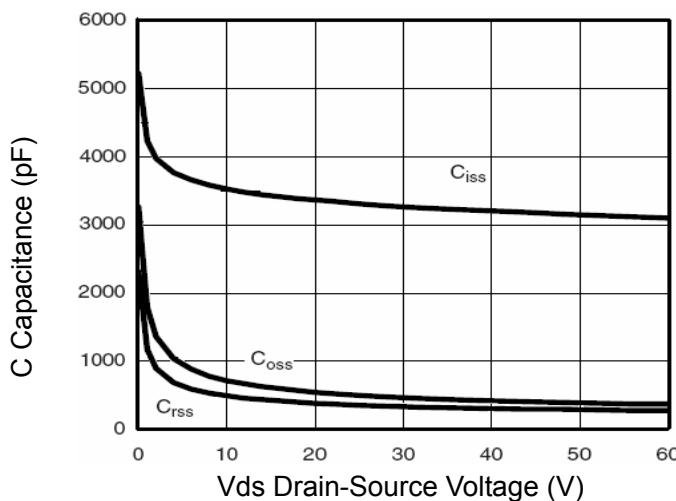


Figure 7 Capacitance vs Vds

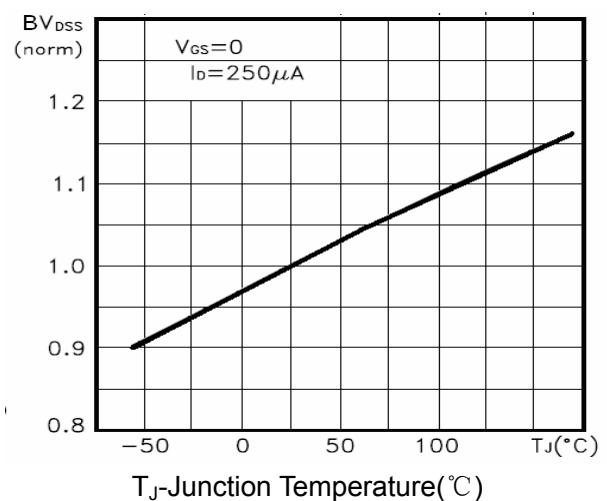


Figure 9 BV_{DSS} vs Junction Temperature

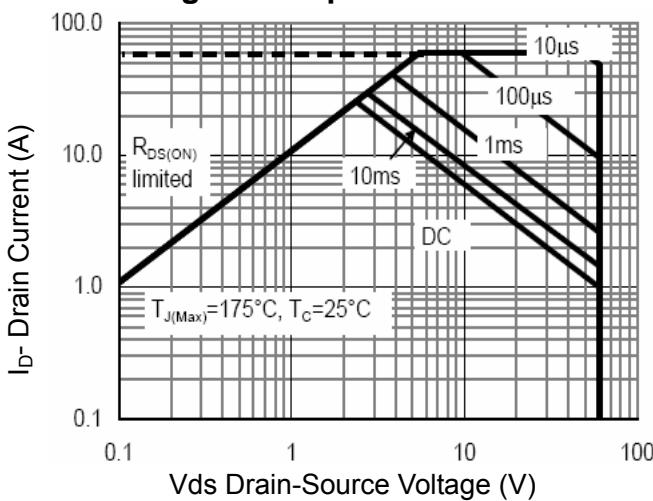


Figure 8 Safe Operation Area

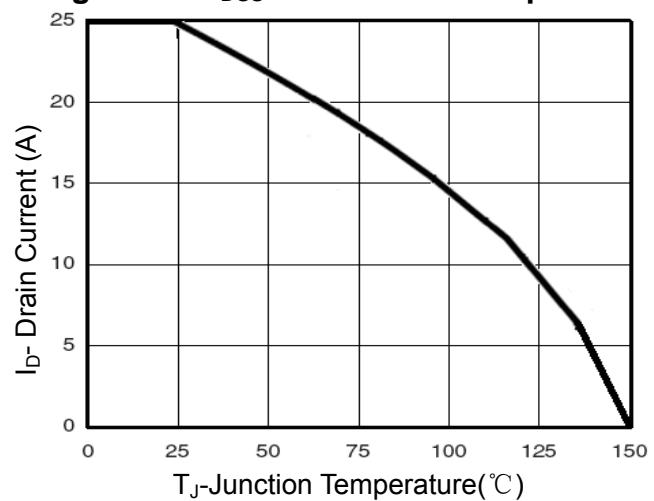


Figure 10 ID Current De-rating

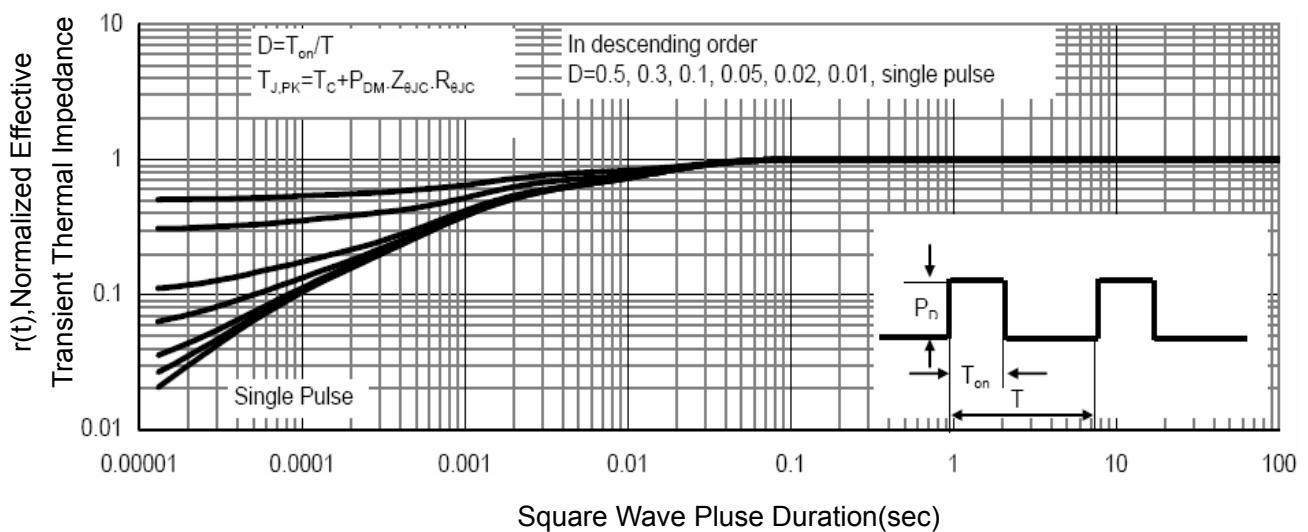
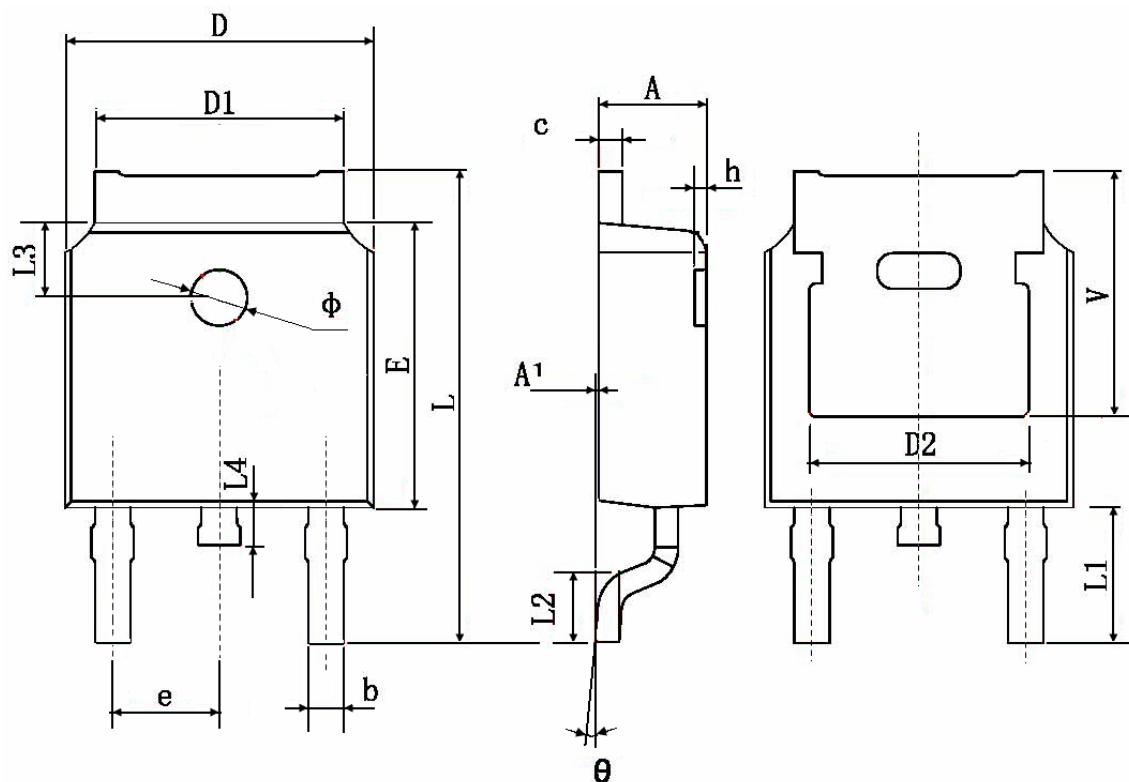


Figure 11 Normalized Maximum Transient Thermal Impedance

TO-252 Package Information


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830 TYP.		0.190 TYP.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 TYP.		0.114 TYP.	
L2	1.400	1.700	0.055	0.067
L3	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	